

Performance of LLRF system

Feng QIU (KEK)

Main Content

- Low Level RF system
- Gain Scanning for Injector
- Experiment on ML cavity
- Summary

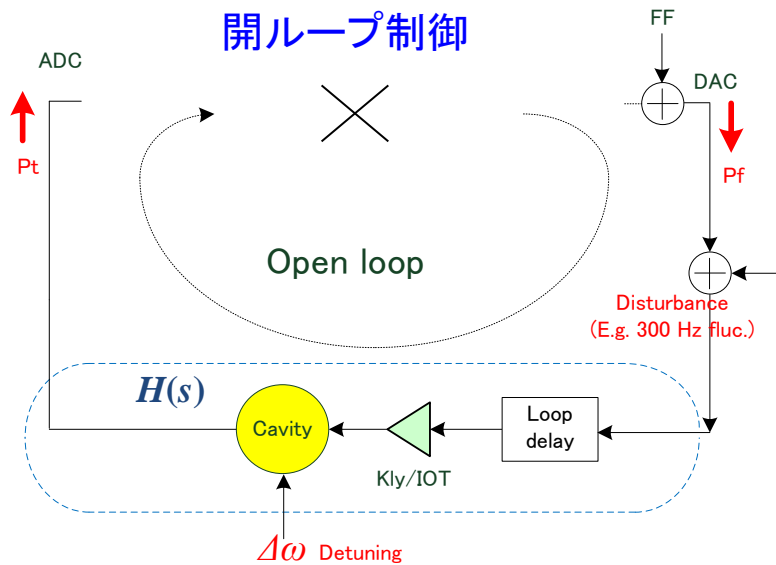
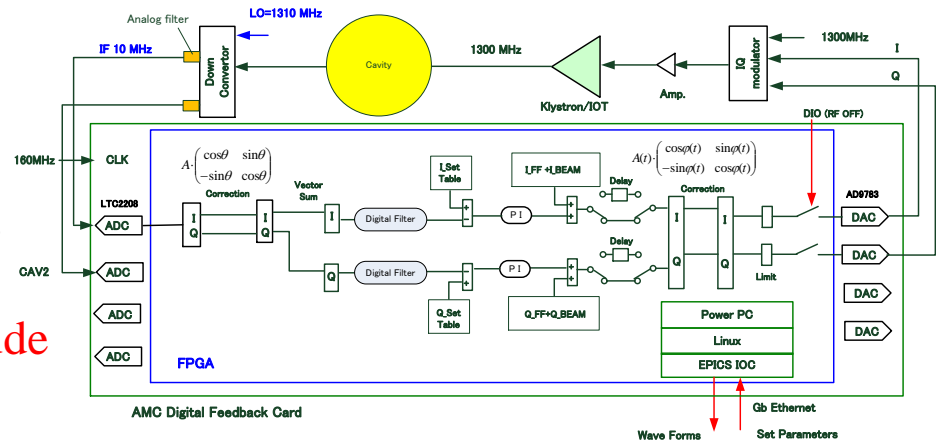
Low Level RF System

■ Main function of LLRF systems.

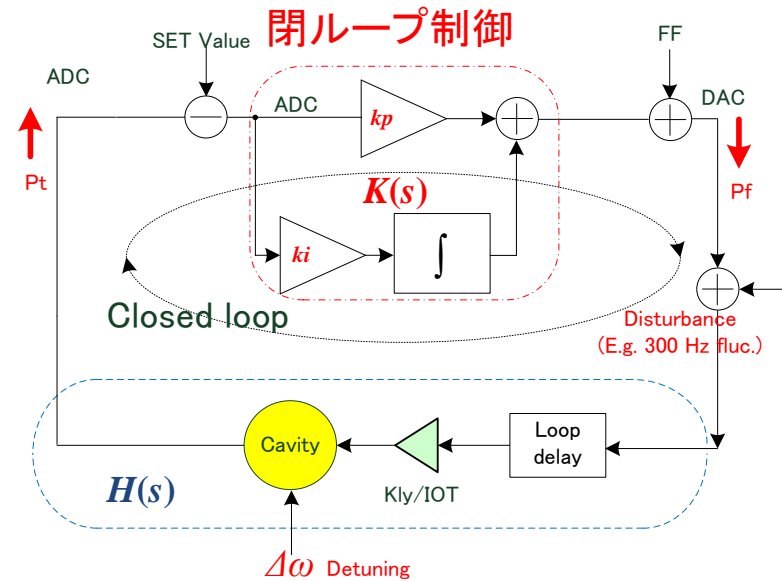
- I. Stabilize the RF field (I&Q Feedback).
- II. Minimize the cavity input power (Tuner Feedback).

■ Closed-loop operation (Feedback) is required to stabilize the RF field.

■ Requirement: 0.1% RMS for amplitude and 0.1 deg. RMS for phase.



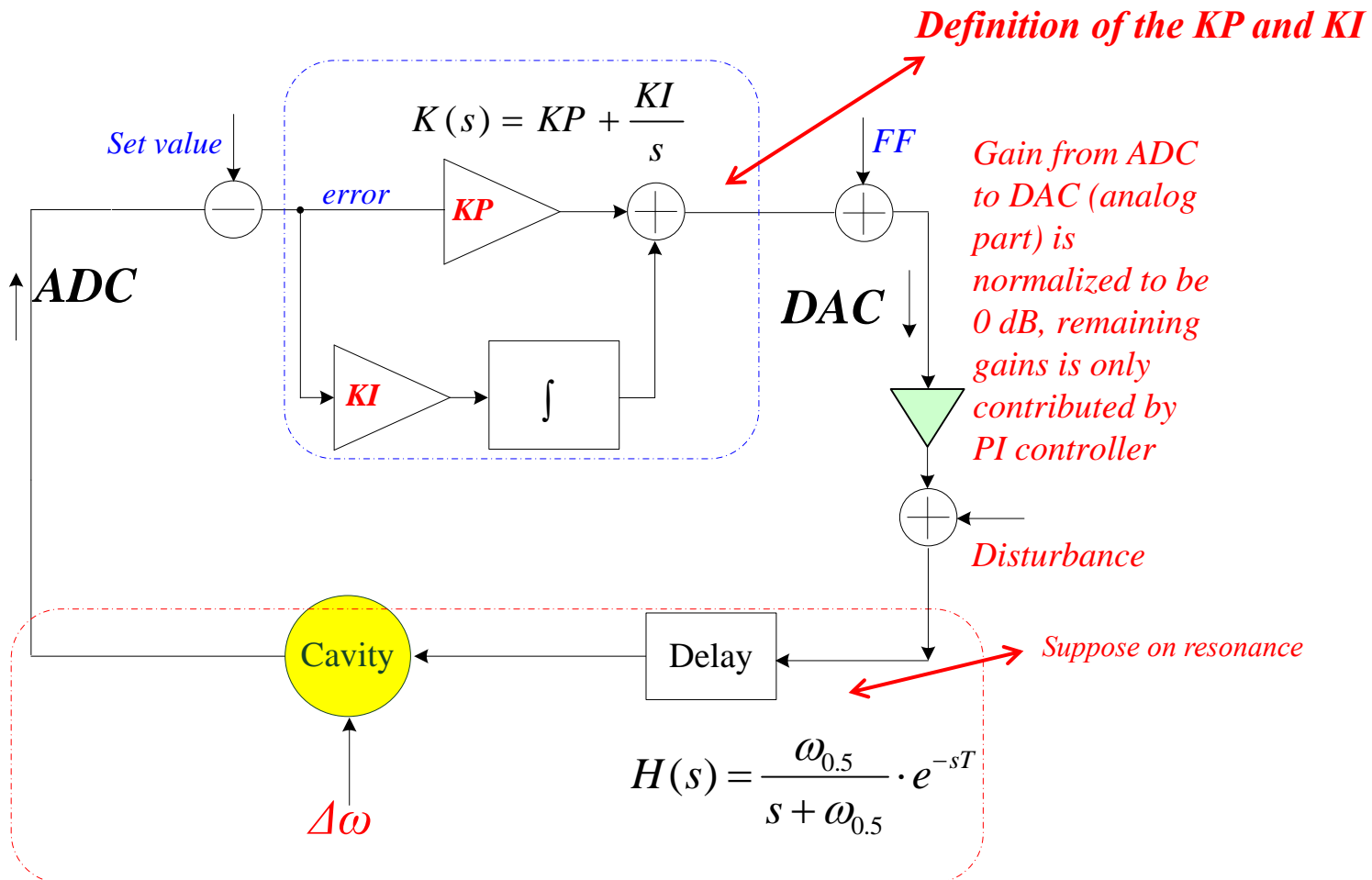
No disturbance suppression!



Disturbance suppression: $H(s)/(1+K(s)H(s))$

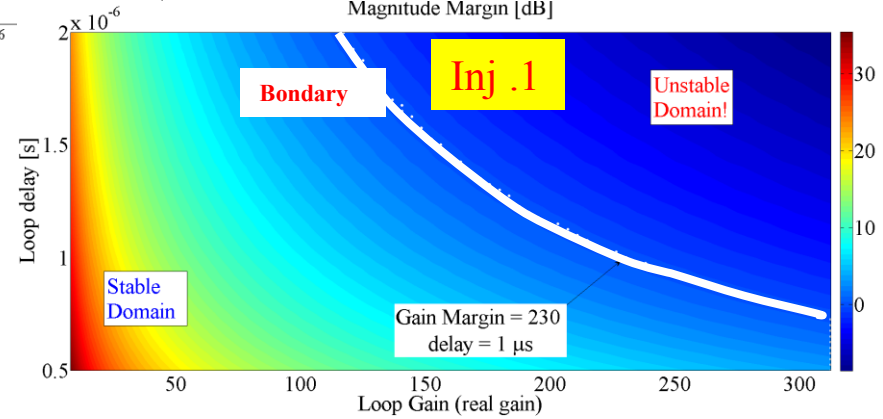
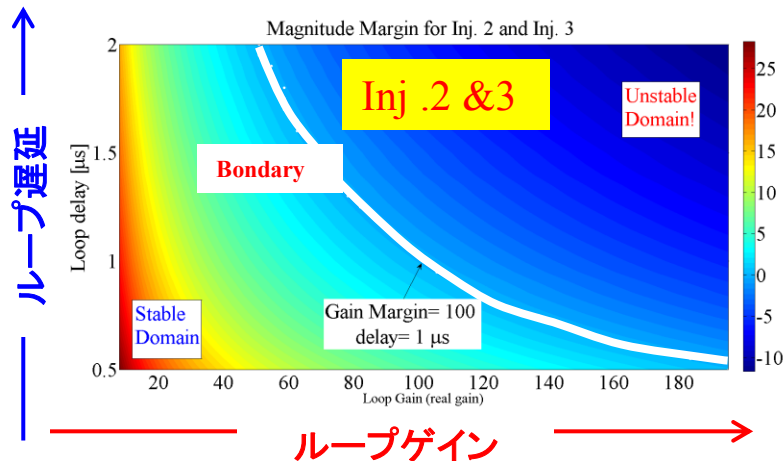
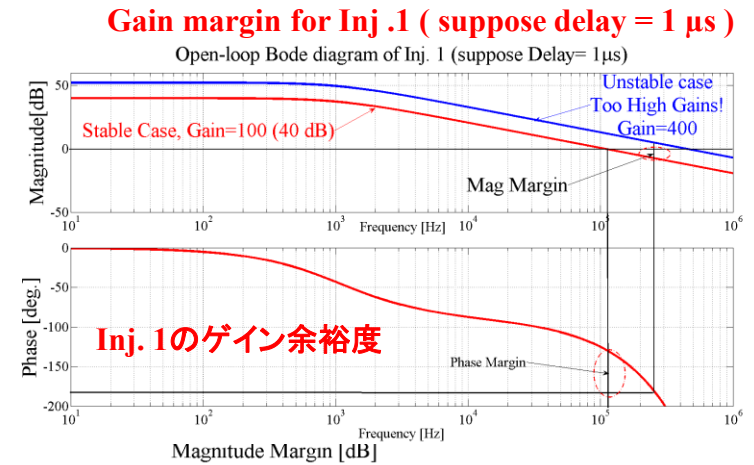
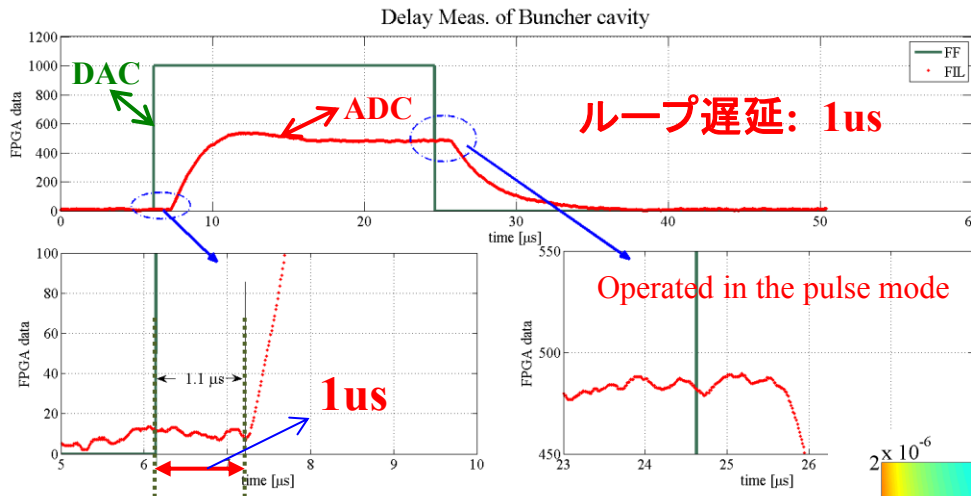
Gain scanning (Definition of Gain)

- Gain-scanning: Scanning different proportional gain KP and integral Gain KI to find out the optimal gains.
- The scanning experiment was carried out at low RF field.



Gain Scanning (Delay measurement)

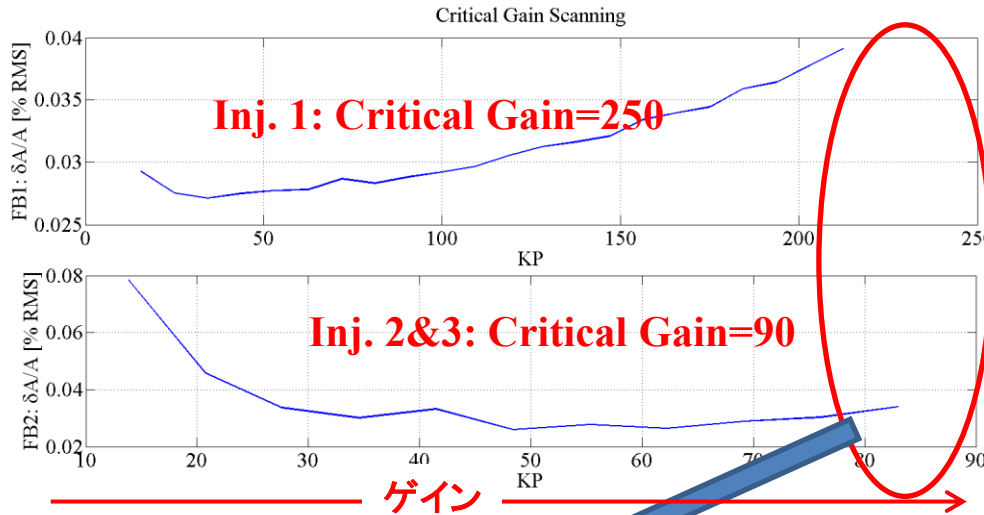
- In order to acquire some priori information about the maximum gain, we have evaluated the loop delay at first due to there is a relationship between the loop delay and the maximum gains.
- Loop delay is measured by exciting the OL system with square wave in the DAC output.



Simulated Gain margin: Inj1=230, Inj. 2&3=100

Gain scanning (Critical gains)

- The Critical gain has measured by the KI=0, KP Scanning.
- If the proportional gain is larger than the critical gain, the loop would be oscillated.



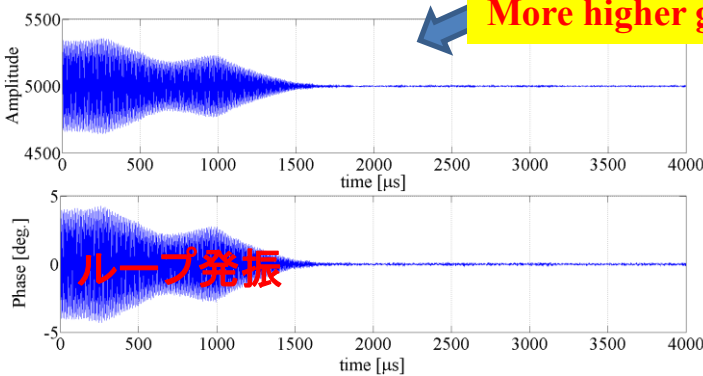
Stb	Bun.	Inj. 1	Inj. 2	Inj. 3
QL	1.1e4	1.2e6	5.8e5	4.8e5
$f_{0.5}$ [kHz]	58	0.54	1.12	1.35

More higher gain!

Gain	Inj. 1	Inj. 2&3
Gain Margin (Sim.)	ゲイン余裕度 230	100
Critical Gain (Meas.)	測定 250	90

↑ 振幅安定度 [% RMS]

振幅
位相

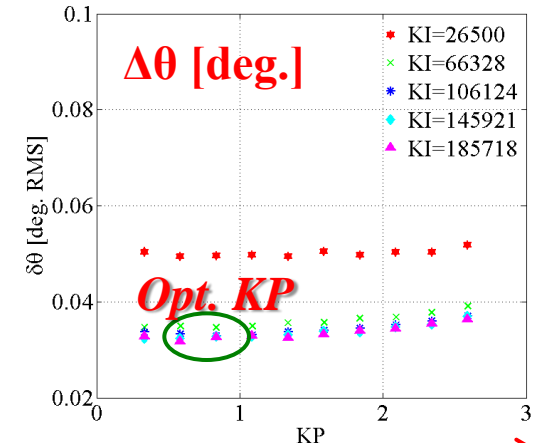
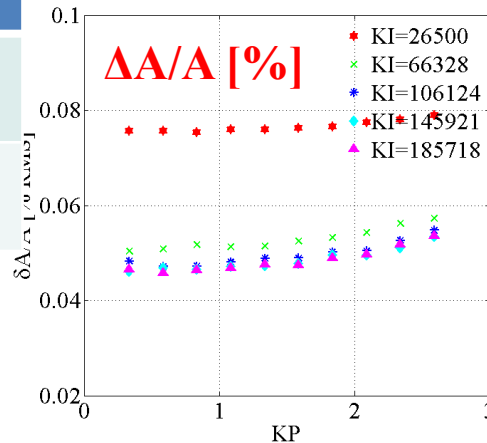


Gain scanning (Buncher)

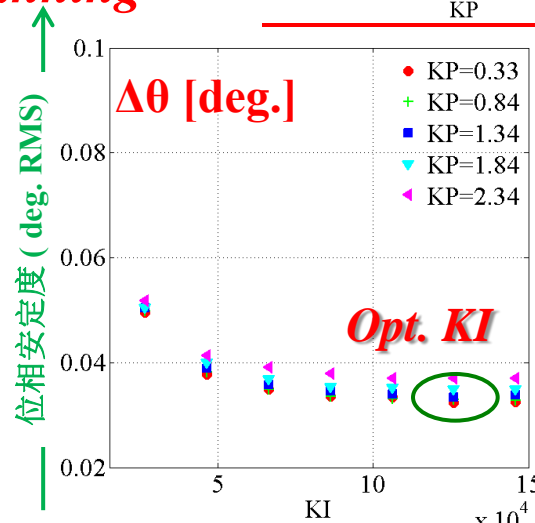
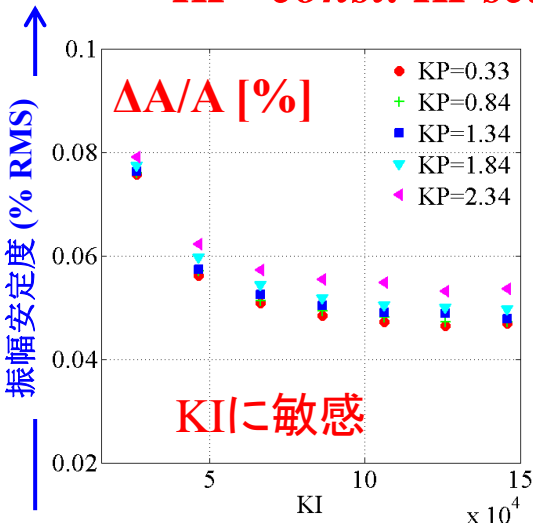
■ High gain is **not** available for Buncher cavity (NC) due to its large bandwidth (QL=1.1e4).

Stb	Bun.	Inj. 1	Inj. 2	Inj. 3
QL	1.1e4	1.2e6	5.8e5	4.8e5
$f_{0.5}$ [kHz]	58	0.54	1.12	1.35

KI=const. KP scanning



KP=const. KI scanning



P ゲイン

最適ゲイン:

$KP_{opt}=0.8, KI_{opt}=1.2e5.$

■ It is clear to see that the integral Gain KI is dominant gain for the Buncher cavity because of the limitation of high proportional gain KP (**not available!**).

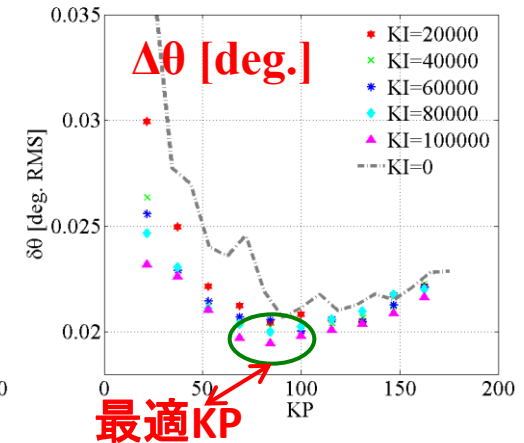
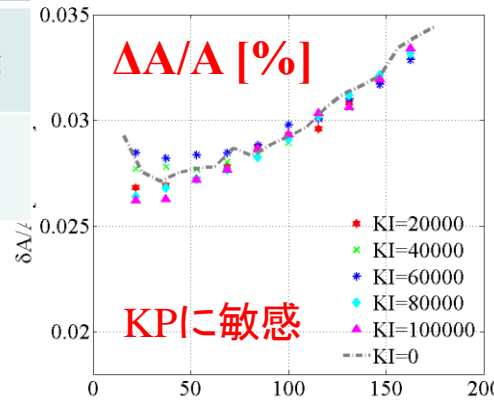
I ゲイン

Gain scanning (Inj. 1)

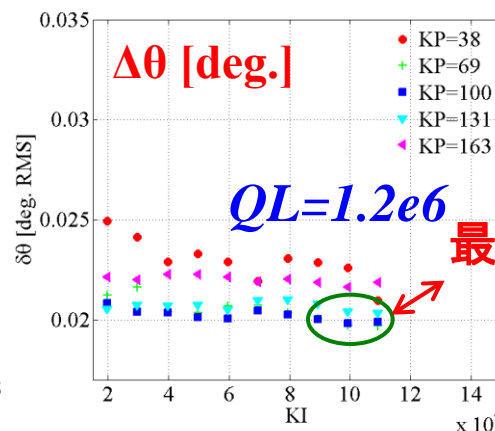
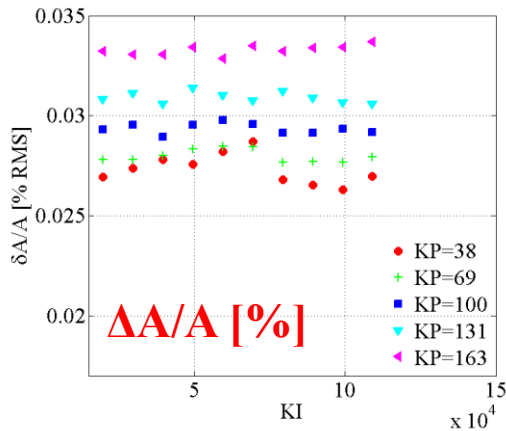
■ High gain is available for Inj. 1 cavities (SC).

Stb	Bun.	Inj. 1	Inj. 2	Inj. 3
QL	1.1e4	1.2e6	5.8e5	4.8e5
$f_{0.5}$ [kHz]	58	0.54	1.12	1.35

KI=const. KP scanning



KP=const., KI scanning



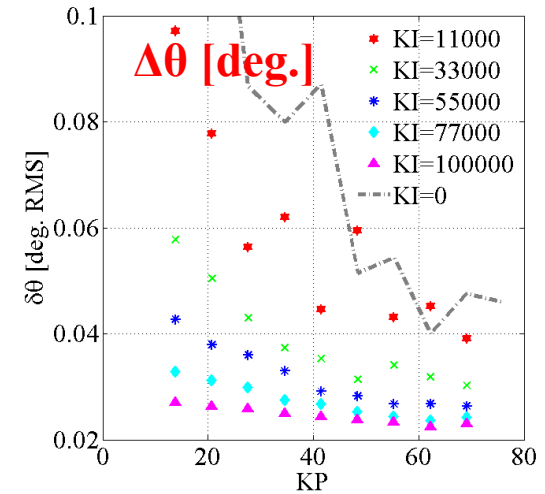
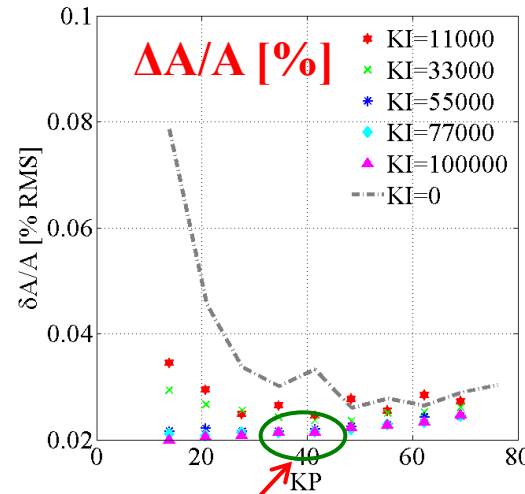
最適ゲイン:
 $KP_{opt}=84, KI_{opt}=1.0e5.$

■ The dominant gain in Inj. 1 is proportional gain (KP), very common in SC cavity controlling.
 ■ High gain controlling can be realized due to its narrow bandwidth.

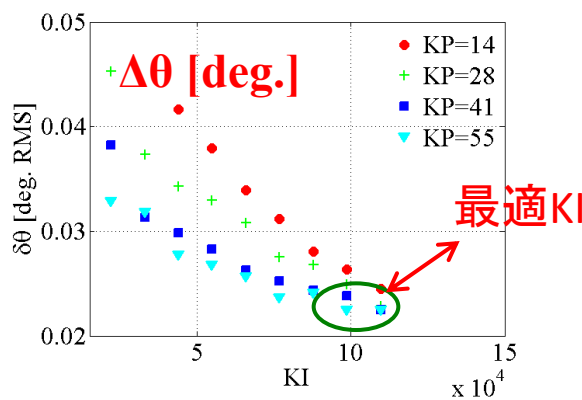
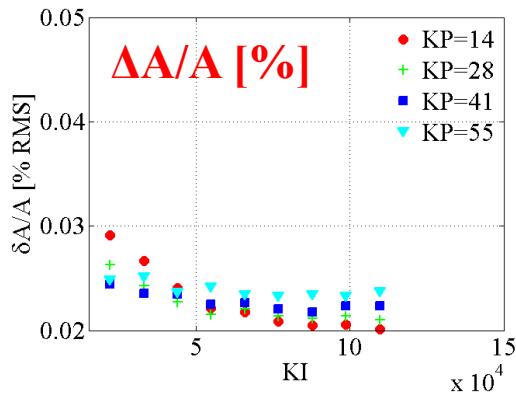
Gain scanning (Inj. 2&3)

- High gain is available for Inj .2 (SC) and Inj .3 (SC). *KI=const., KP scanning*

Stb	Bun.	Inj. 1	Inj. 2	Inj. 3
QL	1.1e4	1.2e6	5.8e5	4.8e5
$f_{0.5}$ [kHz]	58	0.54	1.12	1.35



KP= const., KI scanning



最適ゲイン:
 $KP_{opt}=41, KI_{opt}=1.1e5.$

- Both KI and KP have an effect for Inj. 2&3.
- KI is also significant due to there is an 300 Hz component in the HVPS.

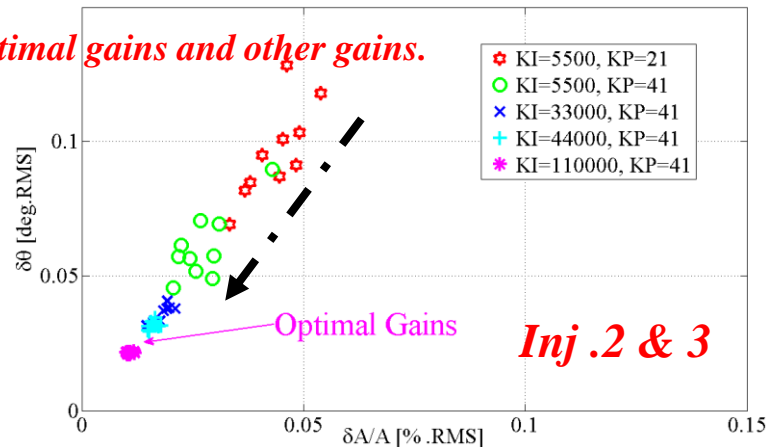
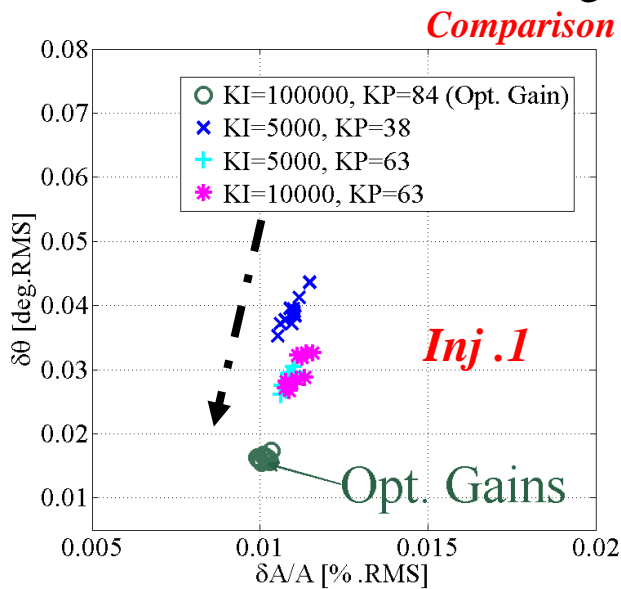
Gain scanning (Conclusion)

Conclusions:

- The proportional gain KP plays an much more important roles in SC cavity and the optimal KP is usually located in the $\frac{1}{2}$ to $\frac{1}{3}$ of the critical gains.
- The integral gain KI is significant in normal cavity due to the limitation of the critical gains.

Vector-sum

Gain	Bun.	Inj. 1	Inj. 2	Inj. 3
Prop. Gain (KP)	0.8	84	41	
Int. Gain (KI)	1.2e5	1.0e5	1.1e5	About $\frac{1}{2}$ to $\frac{1}{3}$
Critical Gain	3	230	90	
$f_{0.5}$ [kHz]	58	0.54	1.12	1.35

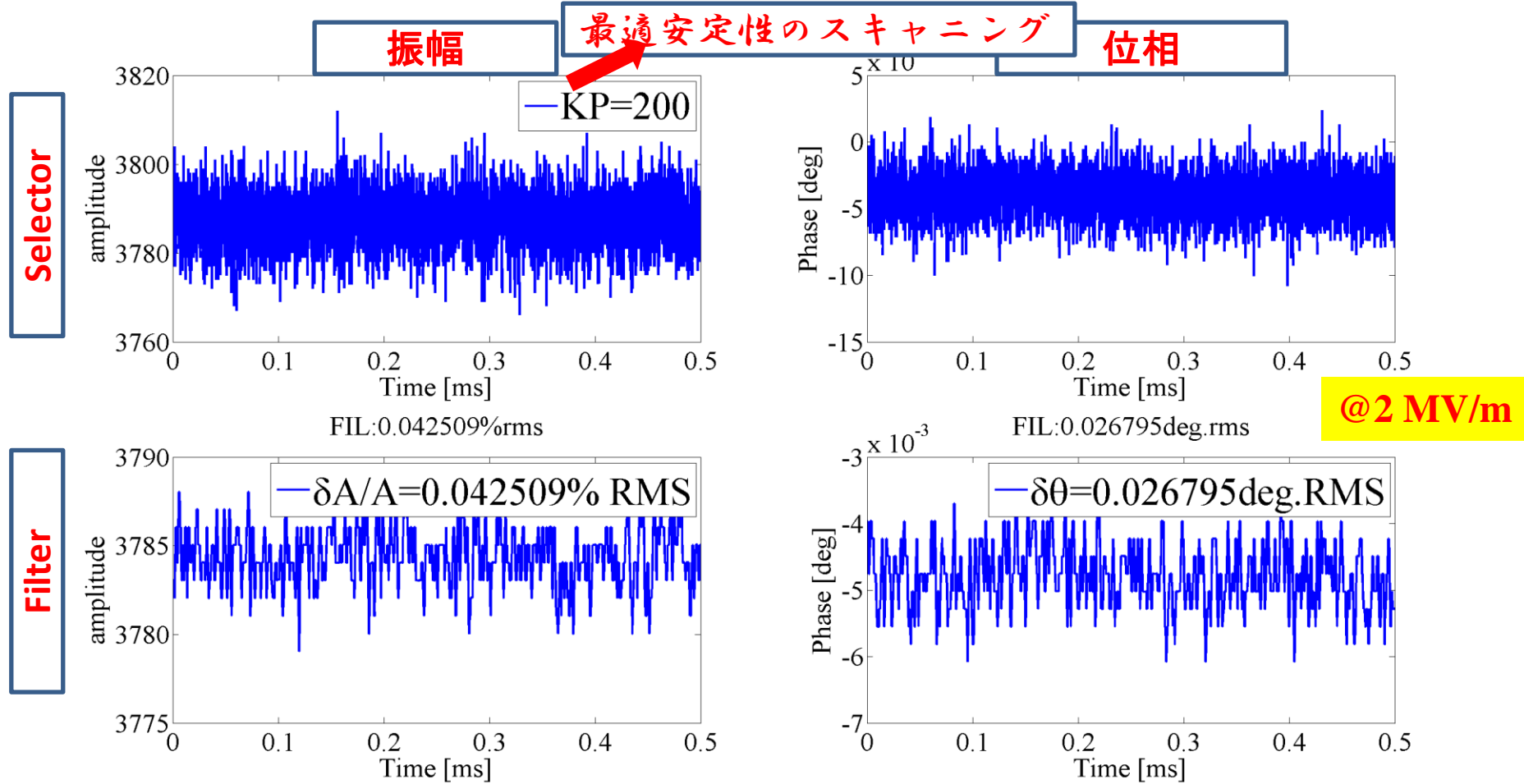


- The performance would be best in the optimal gain case.
- The amplitude and phase stability of Inj. 1 and Inj. 2&3 can be **0.01% RMS** and **0.02 deg. RMS**, respectively.

Experiment on ML (ML1)

- The process of the ML1 gain scanning

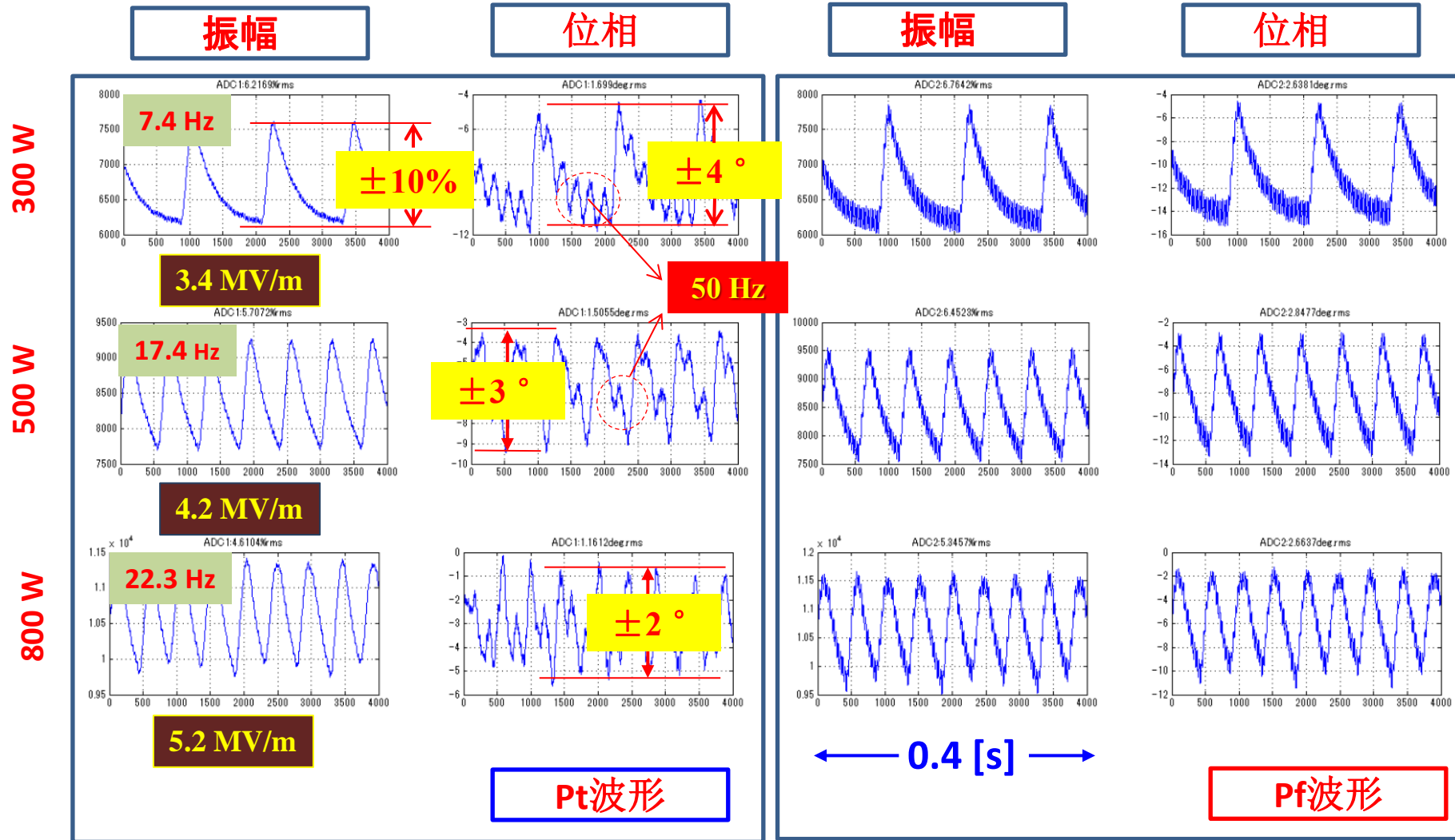
Here KP is CSS input parameter (not real gain)!



必要な安定度 (0.1%, 0.1 deg.)

Experiment on ML (ML2 IOT)

■ Performance of the IOT in ML2.



開ループ制御

Experiment on ML (ML2)

Pt 波形

振幅

FIL:0.24243%rms

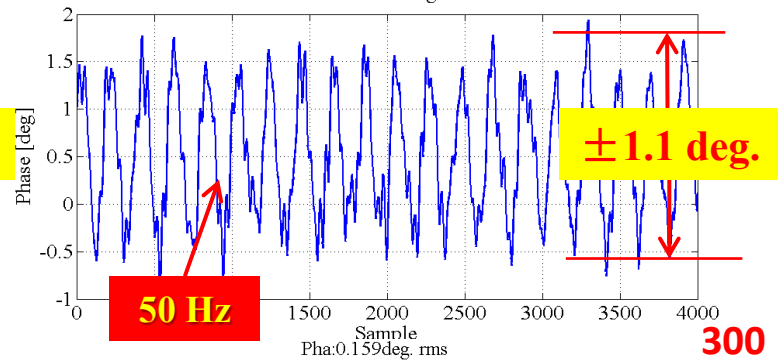
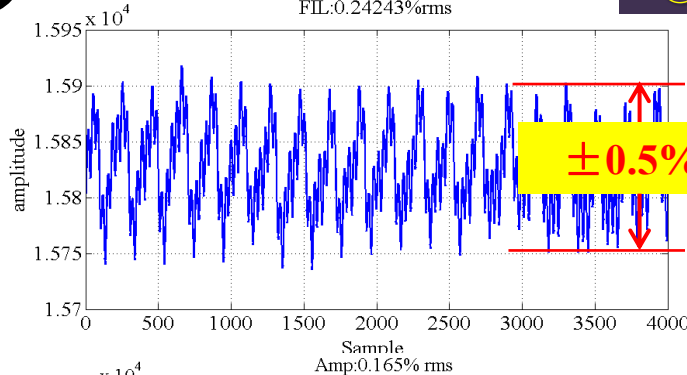
@ 8 MV/m

位相

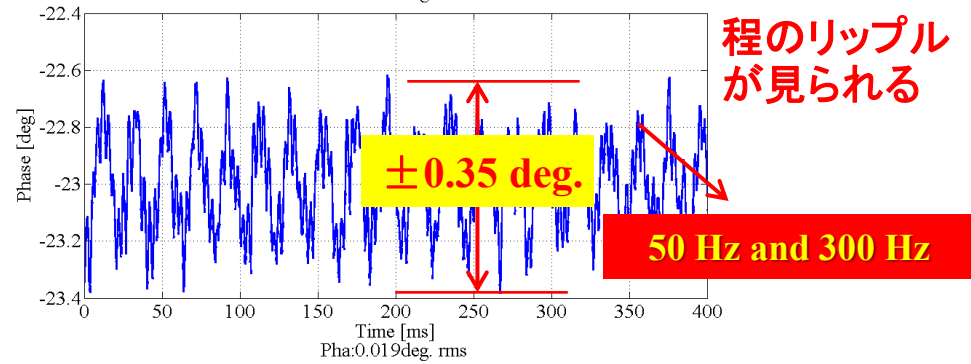
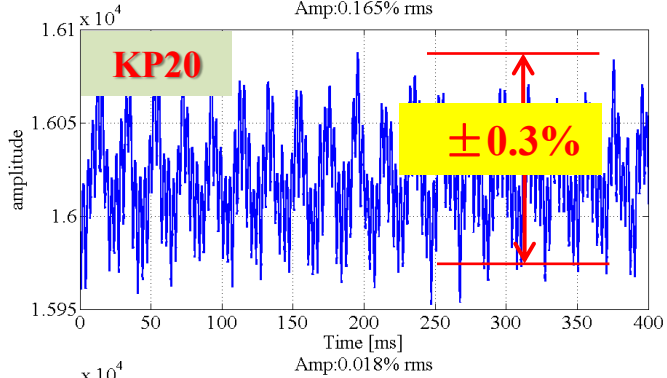
FIL:0.64942deg.rms

安定度 @ 8 MV/m

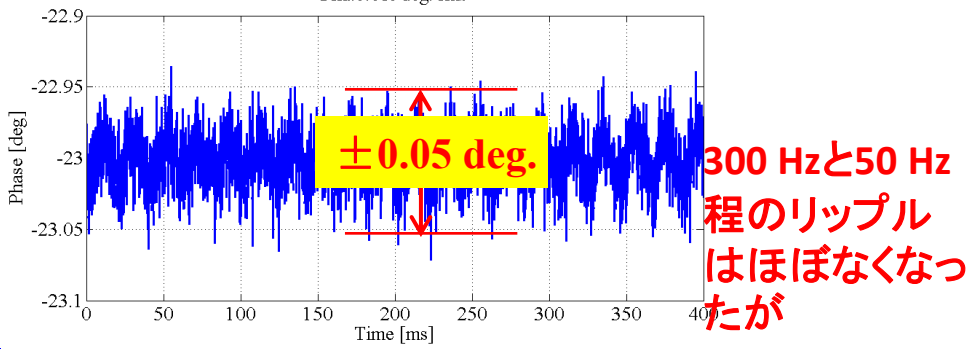
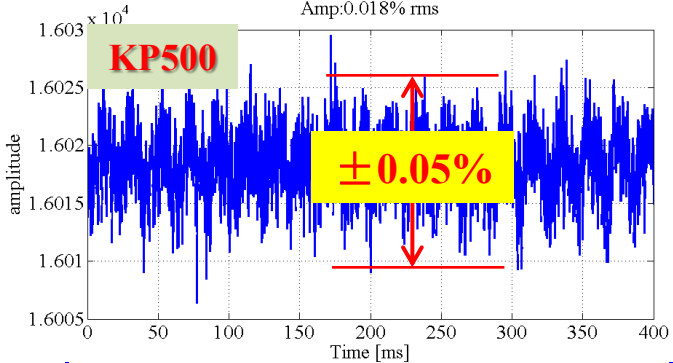
FF



FB (Low)



FB (High)



0.4 [s]

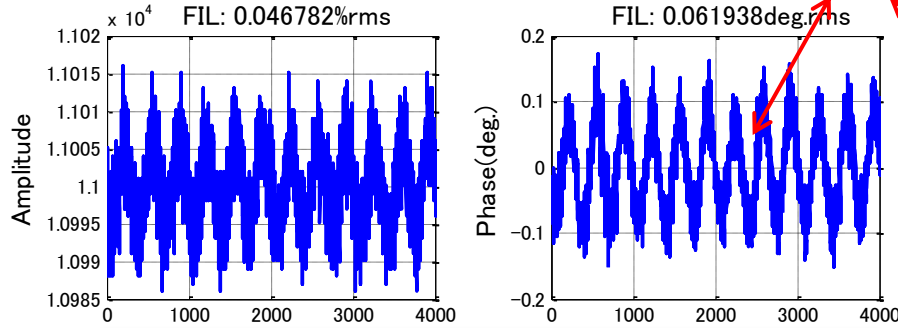
Performance (June)

Pt 波形

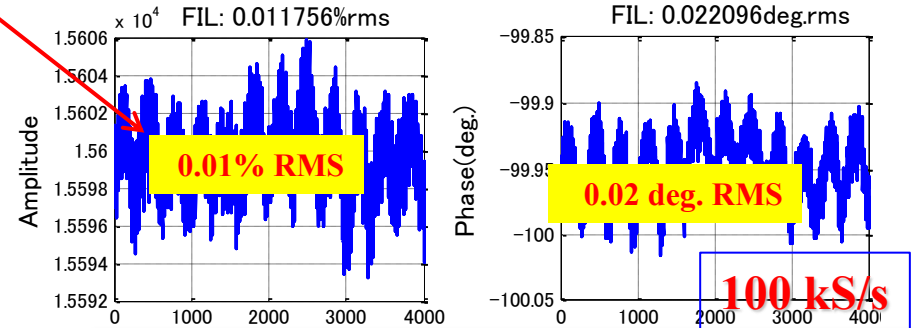
FB0 (Buncher)

300 Hz fluc. from HV
Power Supply

FB2 (Vector-sum of Inj. 2 and Inj. 3)



Amp 0.05% rms, Phase 0.06 deg. rms



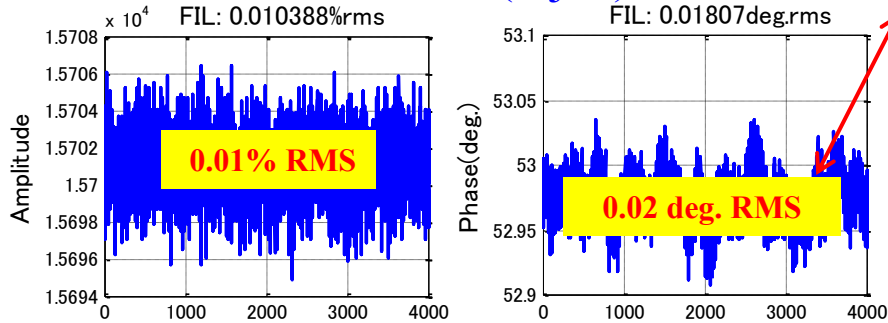
Amp: 0.01% rms, Phase 0.022 deg. rms

100 kS/s

Selections of KP and KI are based on the gain scanning experiment!

FB1 (Inj. 1)

No dominant



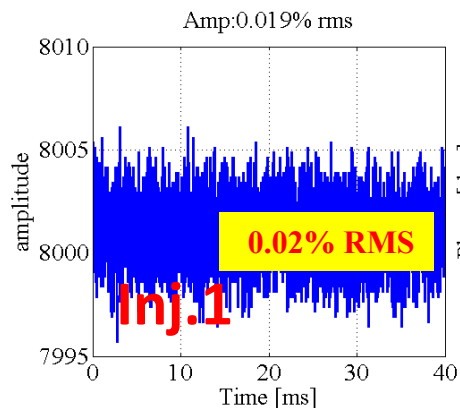
Amp: 0.01% rms, Phase 0.02 deg. rms

	$\Delta A/A$ [RMS]	$\Delta\phi$ [RMS]	Loop Delay
Bun.	0.05%	0.06 deg.	1.1 μ s
Inj. 1	0.01%	0.02 deg.	1.1 μ s
Inj. 2&3	0.01%	0.02 deg.	1.1 μ s

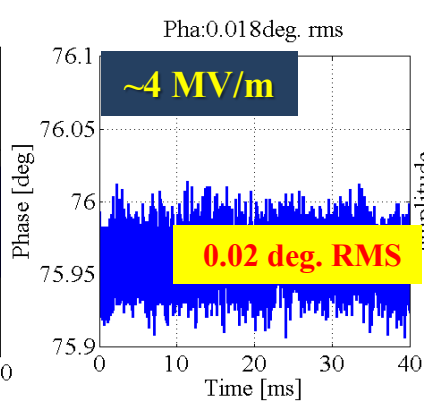
必要な安定度 (0.1%, 0.1 deg.)を満足!

Performance (Dec.)

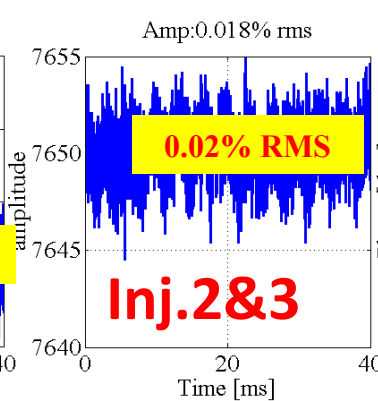
振幅



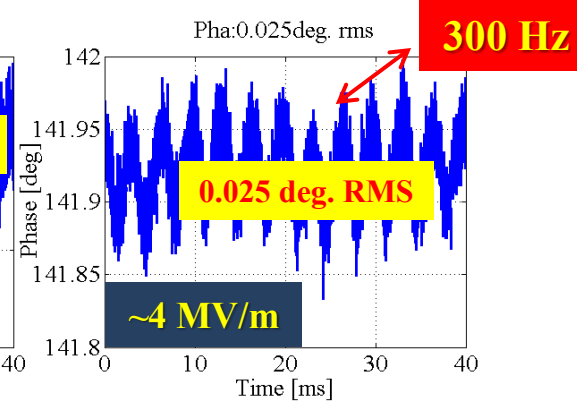
位相



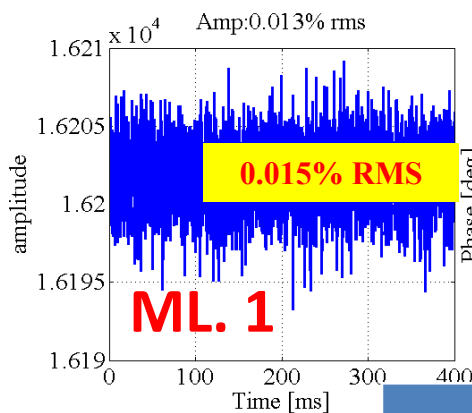
振幅



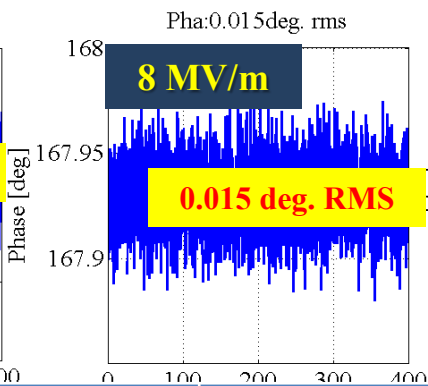
位相



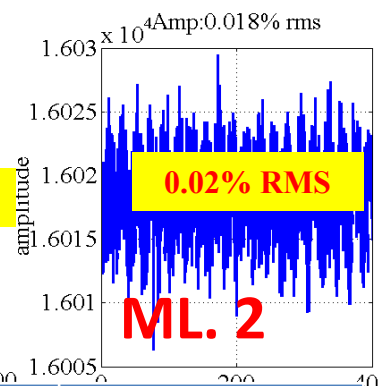
振幅



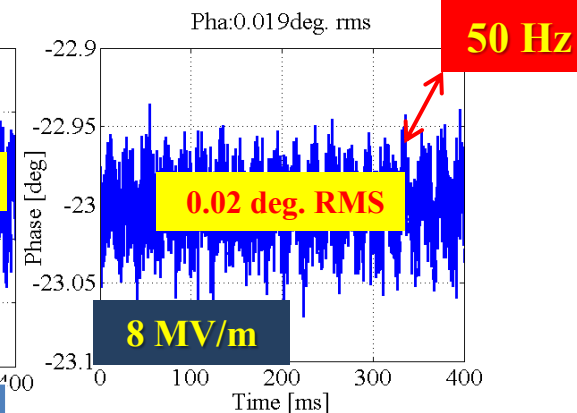
位相



振幅



位相

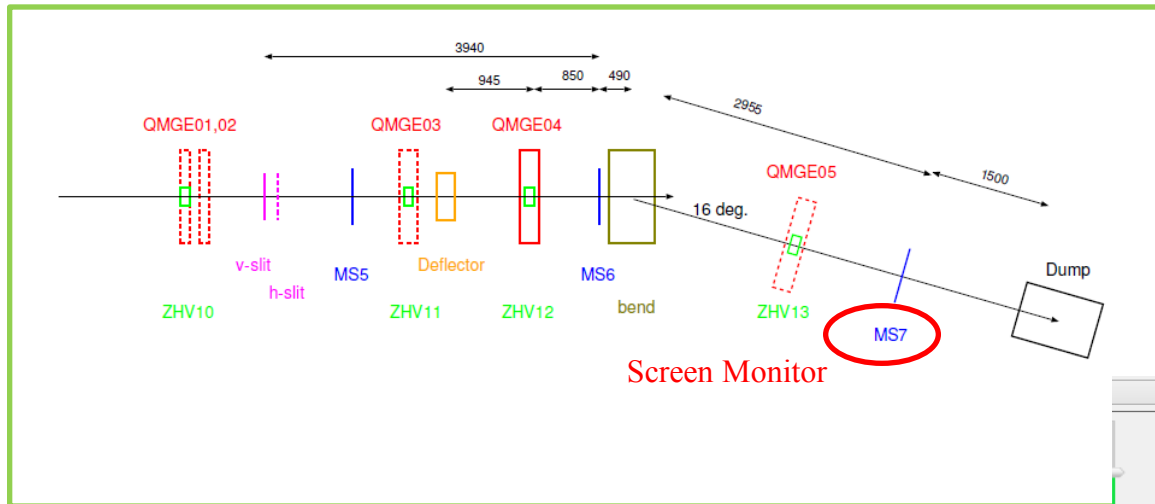


	$\Delta A/A$ [RMS]	$\Delta\phi$ [RMS]
Inj. 1	0.02%	0.02 deg.
Inj. 2&3	0.02%	0.025 deg.
ML. 1	0.015%	0.015 deg.
ML. 2	0.02 %	0.02 deg.

必要な安定度 (0.1%,
0.1 deg.)を満足

Performance (Screen Monitor@June)

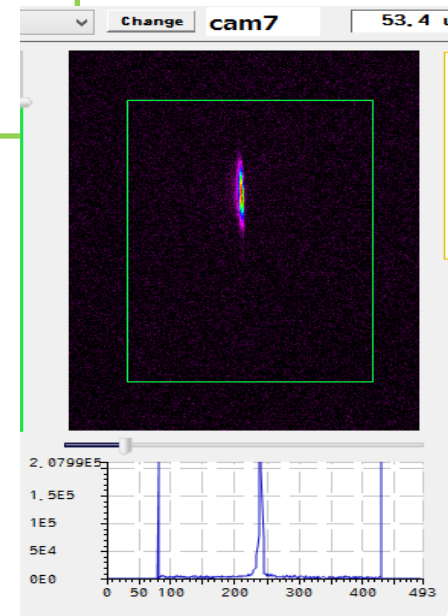
- The beam momentum is measured by screen monitor and determined by the peak point of the projection of the screen.



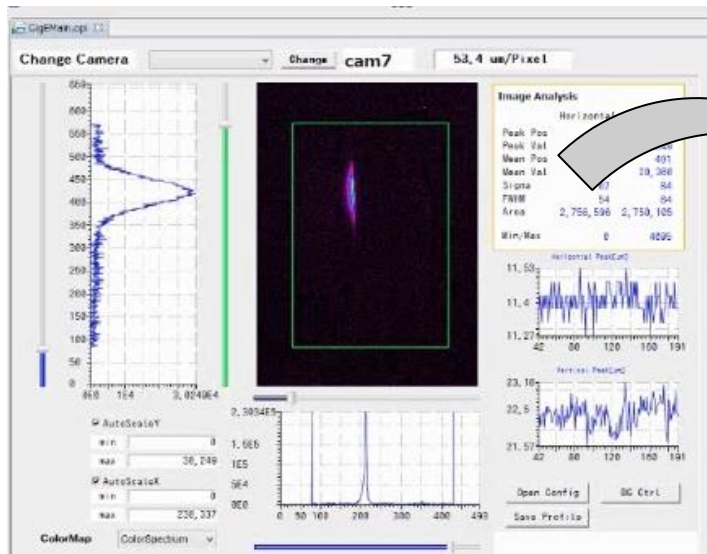
Dispersion @ screen monitor = 0.82m
Resolution = 53.4 $\mu\text{m}/\text{pixel}$
($\Delta P/P=6.5e-5$)

Momentum was determined by the peak point of the projection of the screen.

Attention: Vector-sum error would influence the beam momentum jitter greatly! Thus the phase error btw inj. 2 and inj. 3 should be optimized at first!

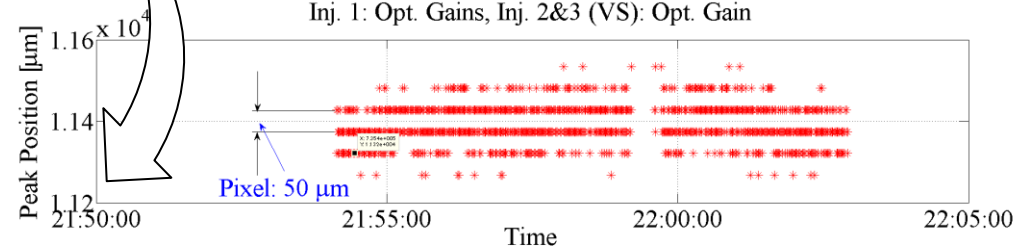


Performance (Beam energy)



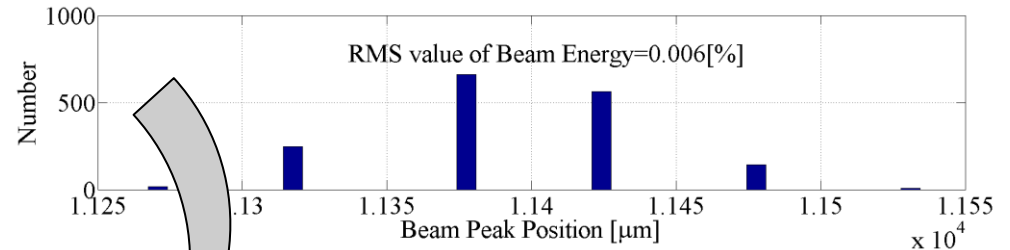
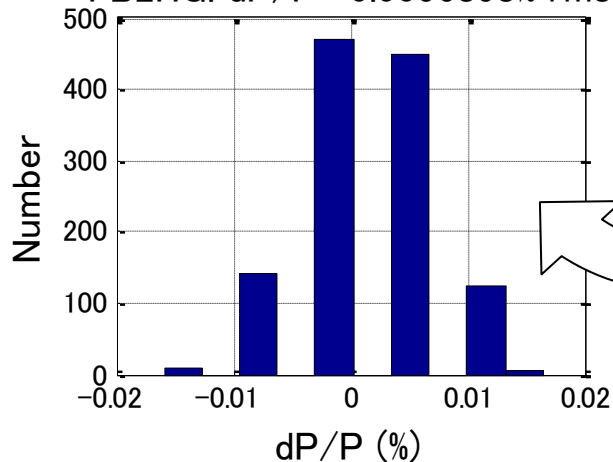
Result of the screen monitor

Inj. 1: Opt. Gains, Inj. 2&3 (VS): Opt. Gain



Beam Energy

FB2HG: $dP/P = 0.0056858\%$ rms



Momentum Jitter= **0.006% rms**

Summary

Summary

- Construction of the RF system for cERL was finished.
- Optimal gains has been determined in the operation for Inj. 1.
- IOT has some oscillation.
- Very good beam momentum.

Question?

Thank you very much for your attending

Back up

Performance (300 Hz Fluctuation)

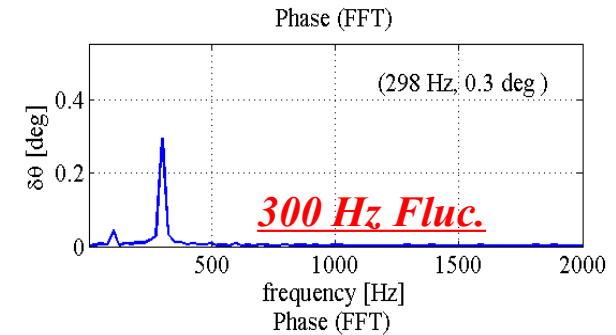
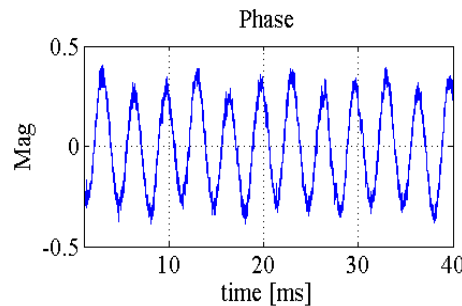
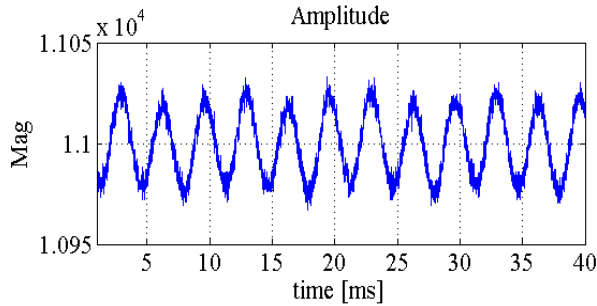
- The 300 Hz fluc. at Inj2&3 and Buncher cavity during CL/OL operation. This 300 Hz fluctuation would influence the system performance.
- The Inj. 1 LLRF system doesn't not has evident dominant components.

Amp.

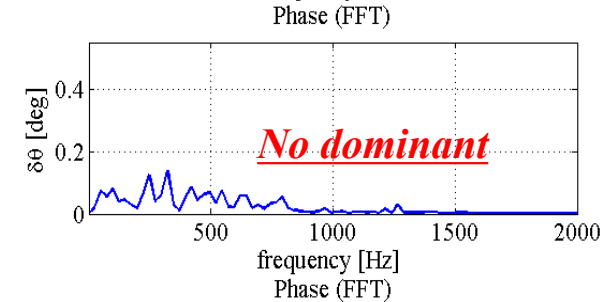
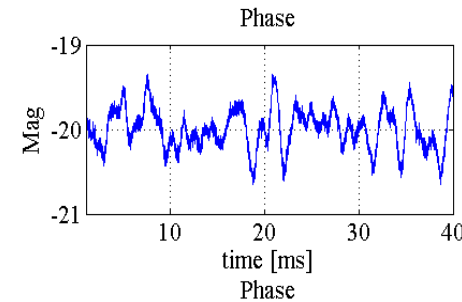
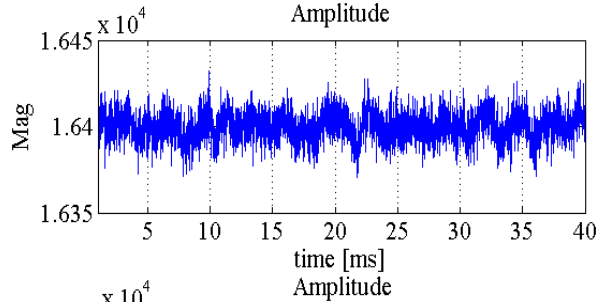
Pha.

Pha. (FFT)

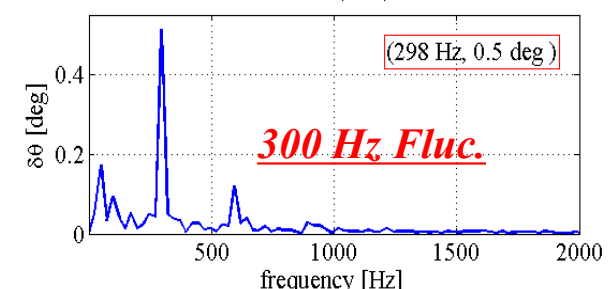
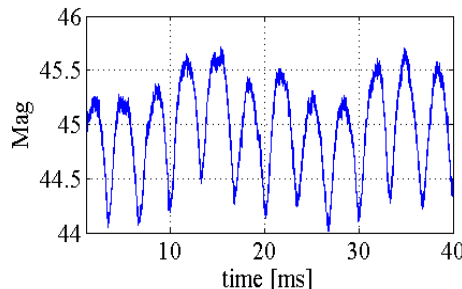
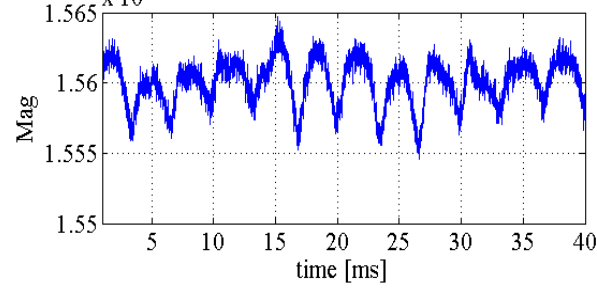
Bun.



Inj.1



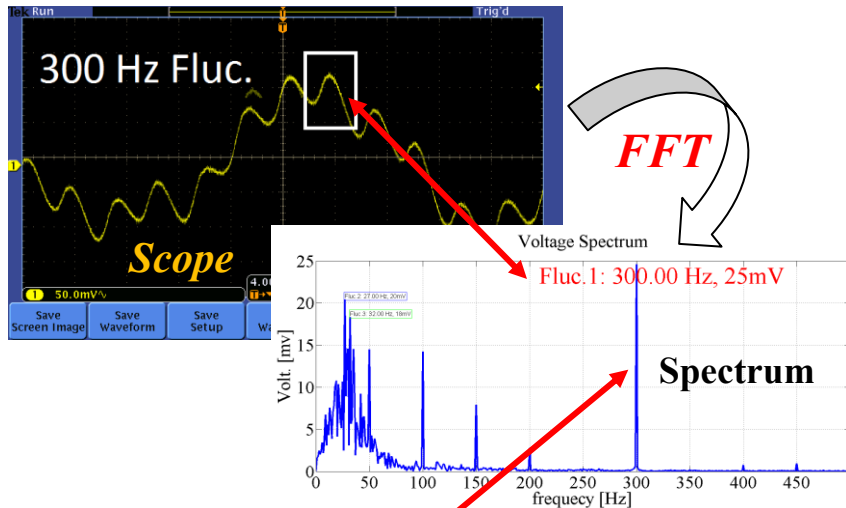
Inj.2&3



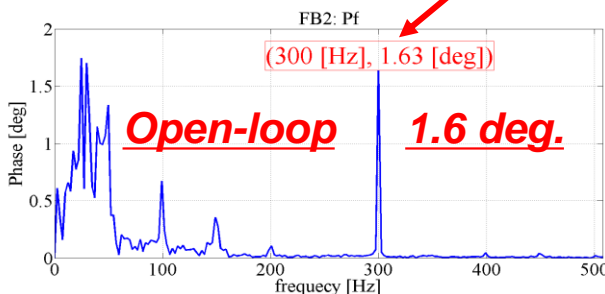
Performance(300 Hz fluc. suppression)

- The Power supply is the main source of the 300 Hz component.
- The RF fluctuation agrees well with the PS fluctuation (suppose 10 deg /HV%, then the 20mV fluctuation in PS will lead to $10 \text{ deg} \times (100 \times 25 \text{ mV} / 15 \text{ V}) = 1.67 \text{ deg}$).

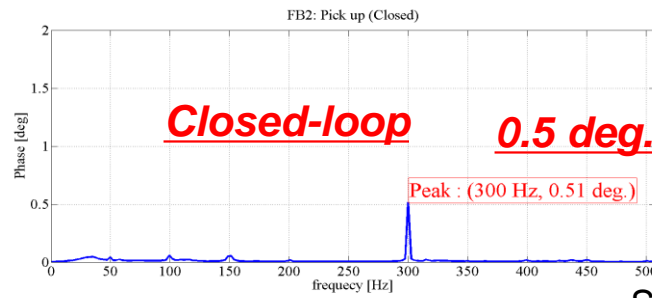
300 KW Kly. High Voltage



	Fluc. @ 300 Hz	Buncher	Inj2&3 (VS)
Open loop	$\Delta A/A$	-43.5 [dB]	-46 [dB]
	$\Delta \theta$	0.9 [deg.]	1.6 [deg.]
Closed loop <i>(KI=5500, KP=0)</i>	$\Delta A/A$	-54 [dB]	-56.5 [dB]
	$\Delta \theta$	0.3 [deg.]	0.5 [deg.]



Cavity input (OL)

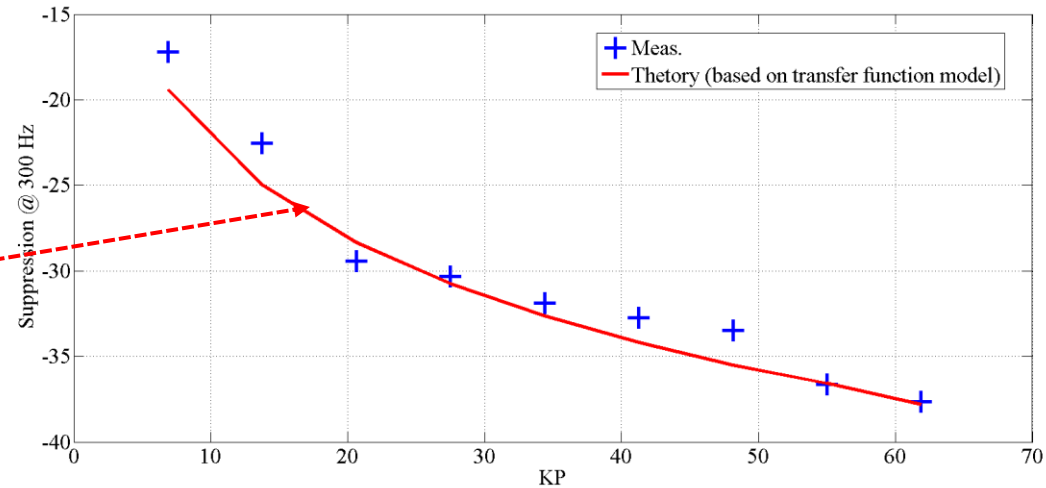
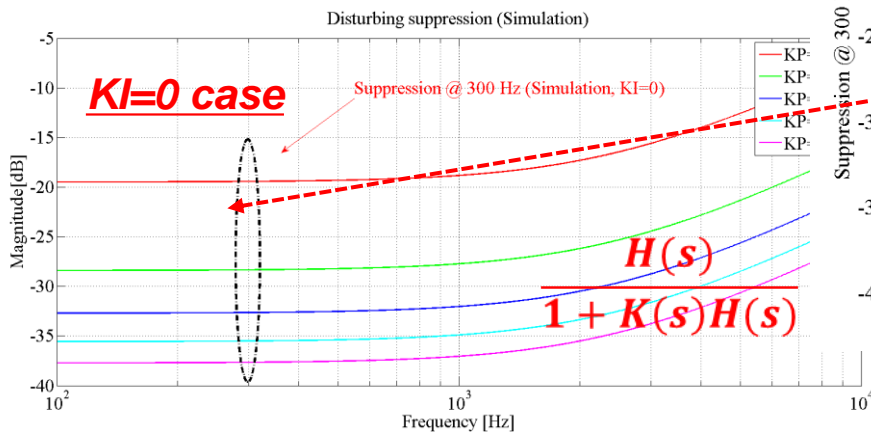
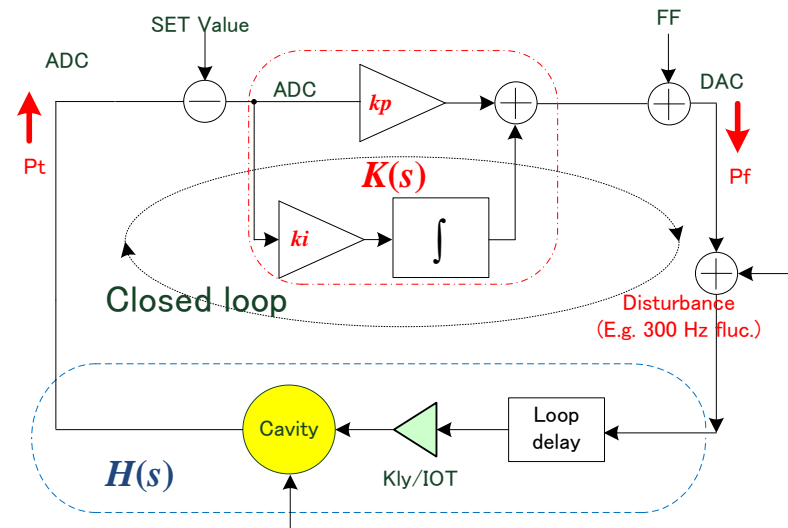
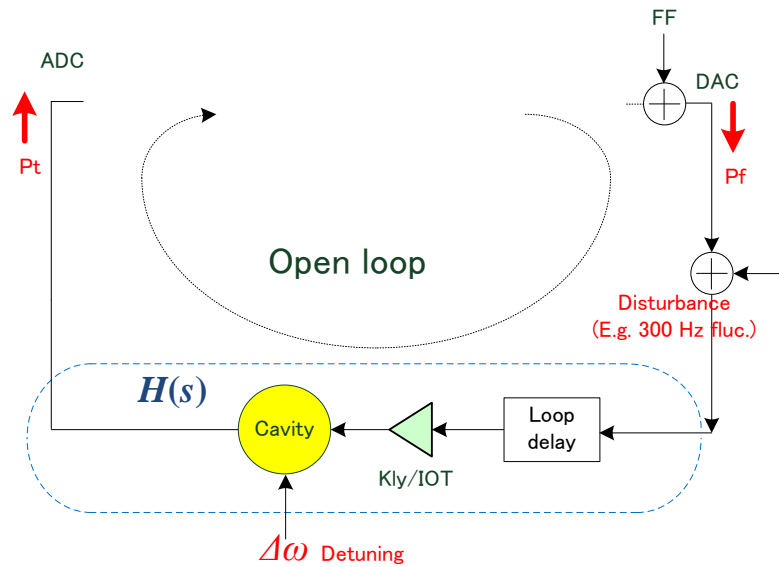


Cavity Pick up (CL)

Clear to see that the 300 Hz component is suppressed by CL operation.

Gain scanning (300 Hz suppression)

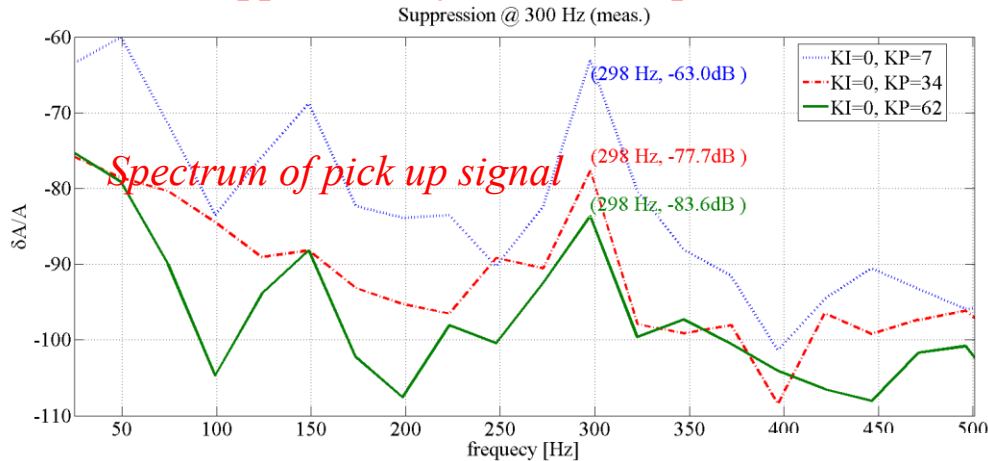
- The 300 Hz fluctuation would be suppressed by higher gains.



Performance(300 Hz fluc. suppression)

- The 300 Hz component is suppressed by high gains.

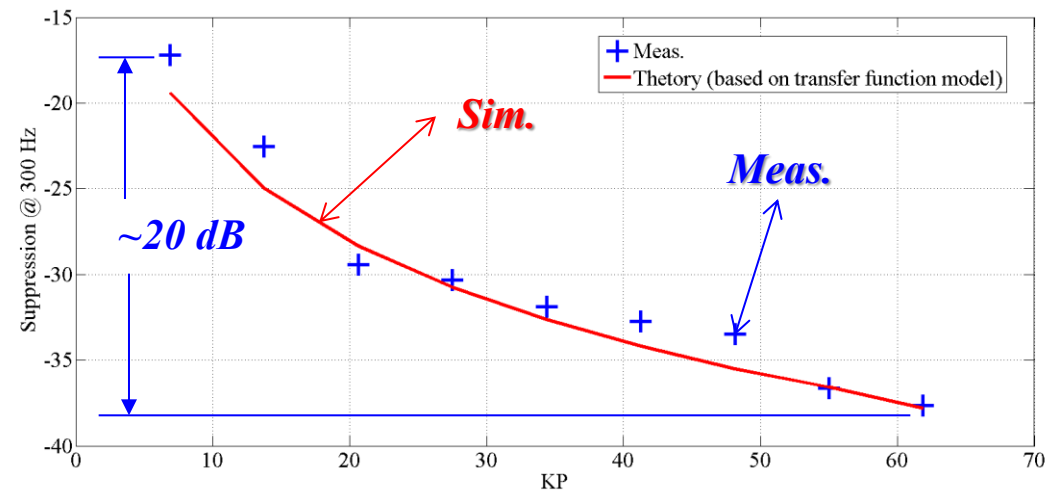
Suppression of 300 Hz component



About 20 dB suppression when increasing KP by 9 times.

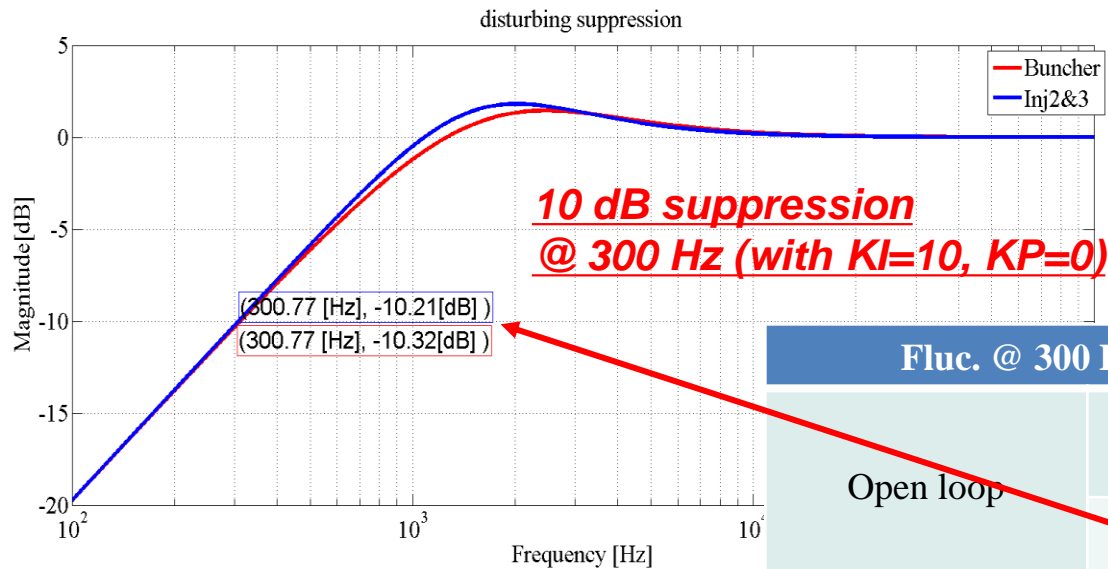
Meas. vs. Simulation

The simulation agrees well with the measured one



Fluctuation at 300 Hz (Source)

■ According to current controlling parameter ($KI=10$, $KP=0$), the 300 Hz component is suppressed by ~ 10 dB (~ 3 times), **not enough**.

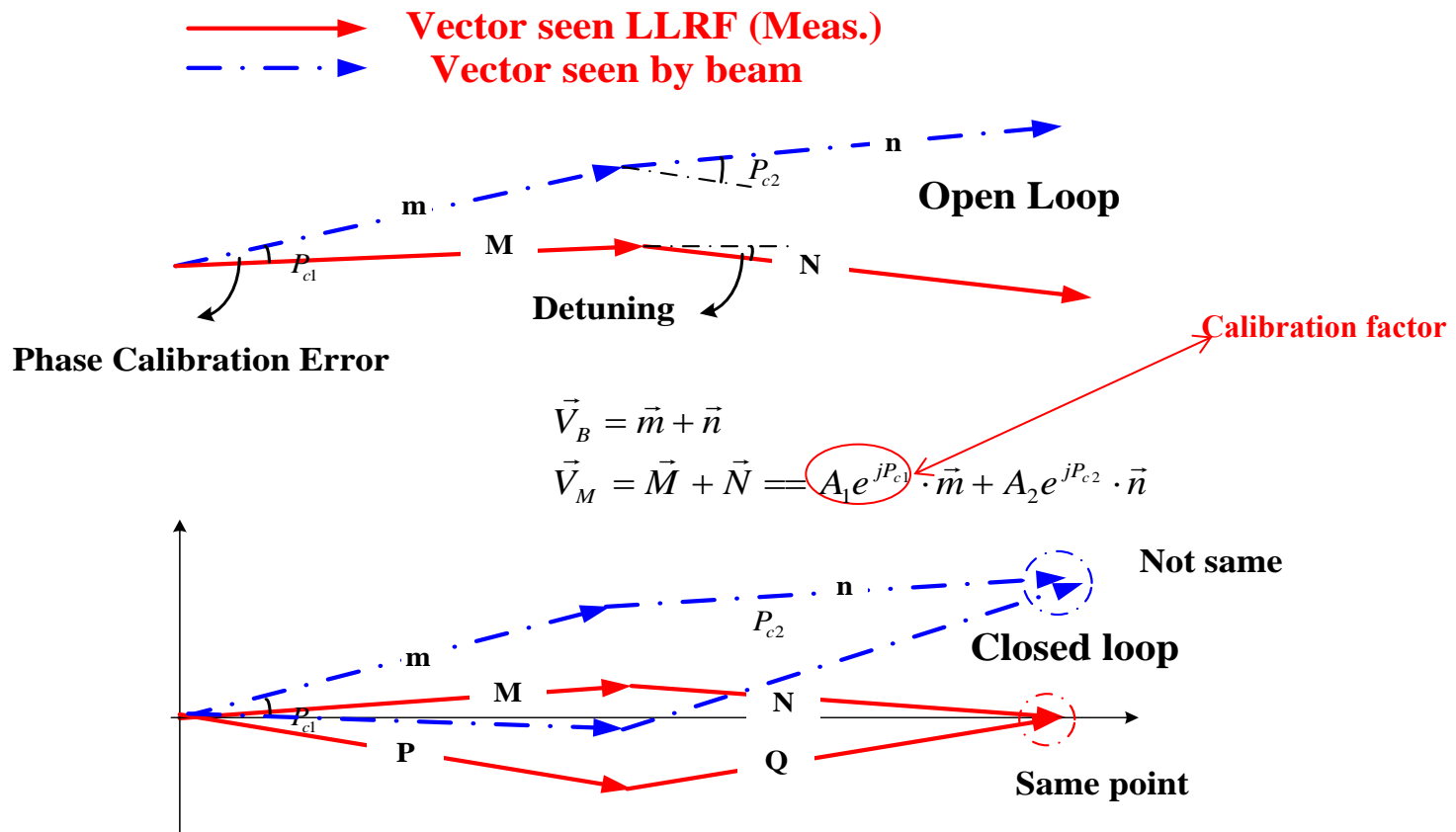


		Fluc. @ 300 Hz	Buncher	Inj2&3 (VS)
Open loop	$\Delta A/A$		-43.5 [dB]	-46 [dB]
	$\Delta \theta$		0.9 [deg.]	1.6 [deg.]
Closed loop	$\Delta A/A$		-54 [dB]	-56.5 [dB]
	$\Delta \theta$		0.3 [deg.]	0.5 [deg.]

($KI=10$, $KP=0$)

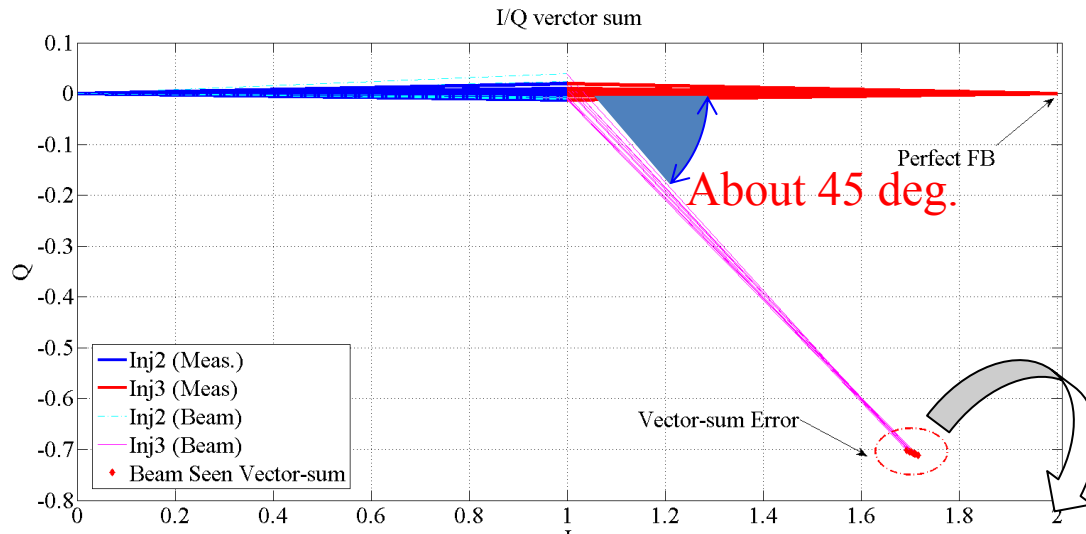
Performance (Vector-sum controlling)

- We have used the vector-sum controlling for Inj. 2 and Inj. 3 (see page 4&5 in this report).
- For vector-sum controlling, the measured vector-sum ($M+N$) which is seen by the FPGA or DSP is different from the true accelerating voltage which is seen by the beam ($m+n$).
- The calibration (phase or amplitude) error would result of vector-sum error



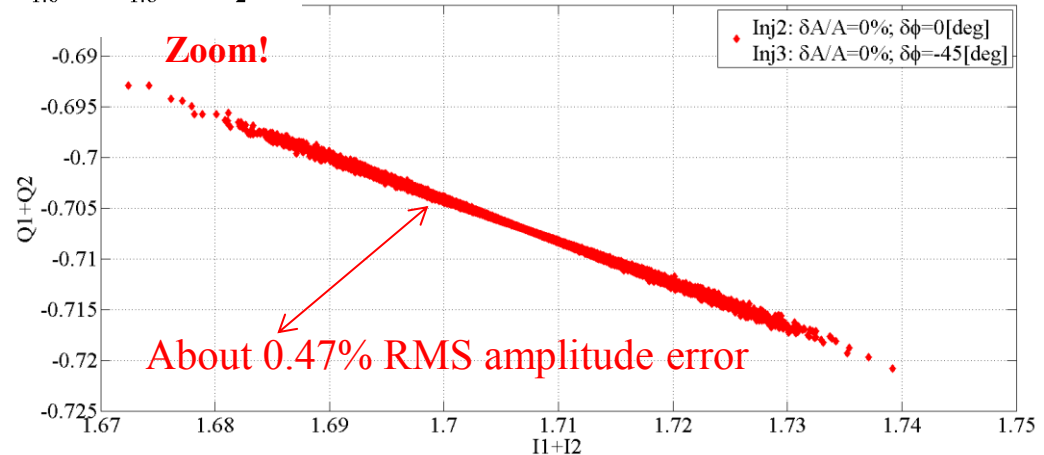
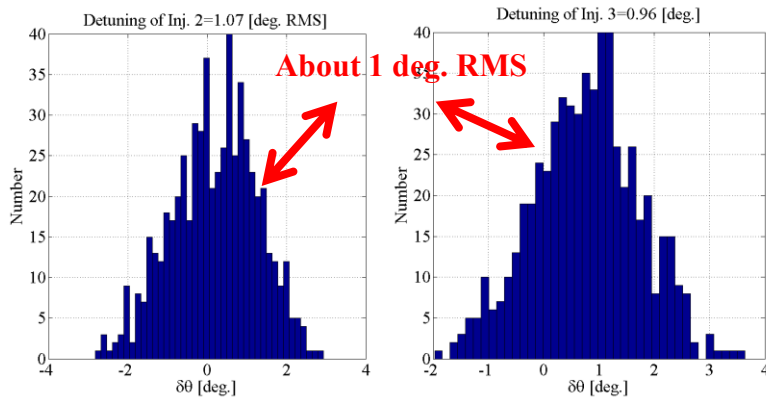
Performance (Vector-sum controlling)

■ Suppose the detuning comply with 1 deg. RMS Gauss distribution, similar with the measured result, then the 45 deg. Phase calibration error would result of 0.47% RMS amplitude vector-sum error.



45 deg. calibration error would result of 0.47% RMS vector-sum error!

Inj2:detuning=1 [deg. RMS], Inj3:detuning=1 [deg. RMS]
 Sum-Error: $\delta A/A=0.469\%$ RMS], $\delta\phi=0.004$ [deg.RMS]



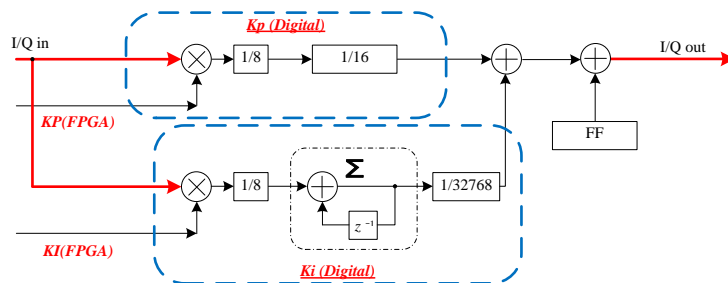
Distribution histogram of the detuning, similar with Gauss distribution.

Gain scanning (definition)

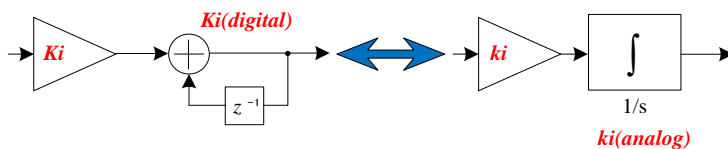
- Gain scanning: determine the optimal controlling gains (@ 2MV).
- Definition of the integral and proportional gains .

- I. FPGA input parameter KP and KI .
- II. Digital Gain Kp and Ki .
- III. Analog Gain kp and ki .
- IV. Real Gains: $A_{Set}/(A_{Set}-A_{Meas.})$

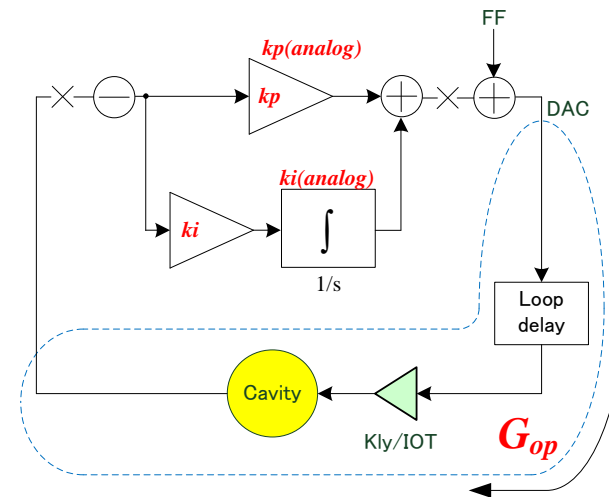
Gains	Integral	Proportional
FPGA	KI	KP
Dig.	$Ki=KI/2^{18}$	$Kp=KP/2^7$
Ana.	$ki=Ki/T_S^{(1)}$	$kp=Kp$
Real	$\approx ki * G_{op}^{(2)}$	$\approx kp * G_{op}$



$KI\&KP$ (FPGA) vs. $Ki\&Kp$ (dig.)



Ki (dig.) vs. ki (ana.)



$ki\&kp$ (ana.) vs. real gain $A_{Set}/(A_{Set}-A_{Meas.})$

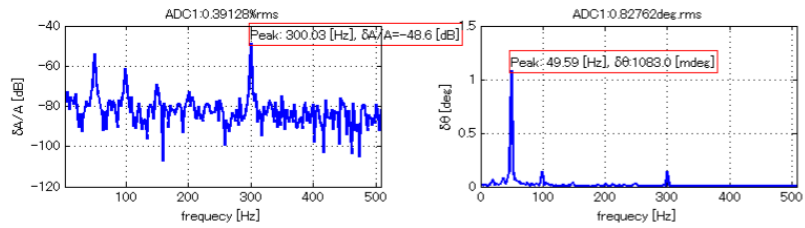
1. T_S is FPGA sampling clock period ($T_S = 1/162.5e6$ in cERL LLRF system)

2. G_{op} is the open-loop gain (Gains from FF to SEL(Fil) during the open-loop operation. For the Inj1 and Inj2&3, $G_{op} \approx 1$ (0 dB).)

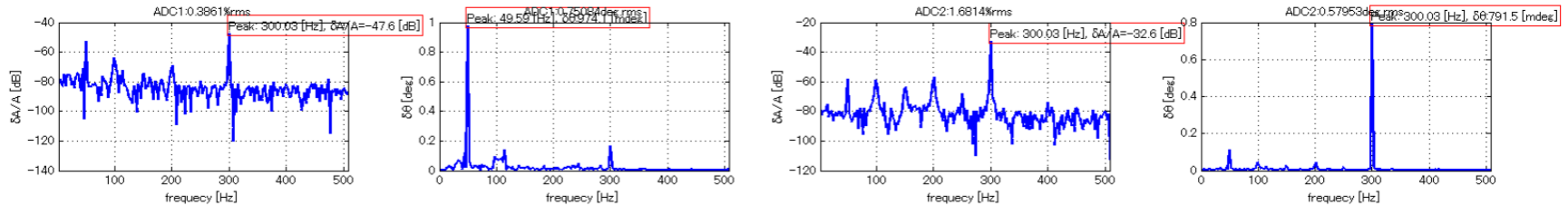
ML2 IOT test

The Spectrum of the IOT (50 W to 200 W)

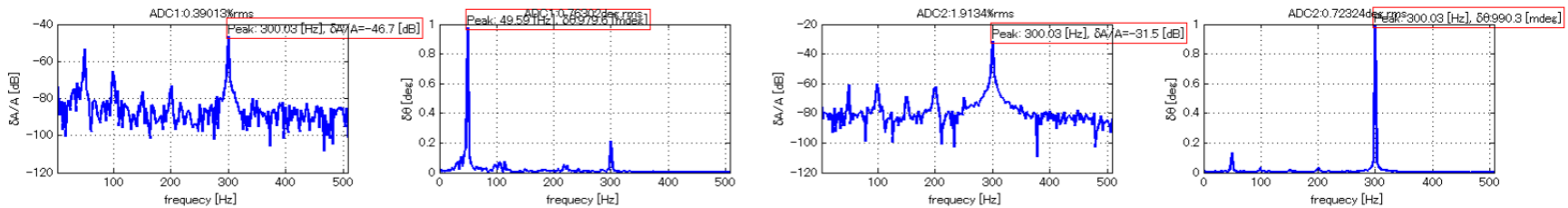
50 W



100 W



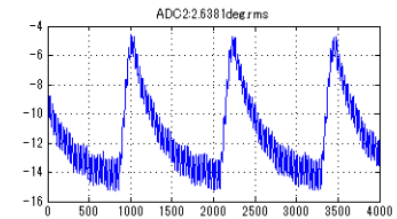
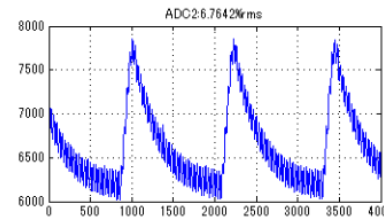
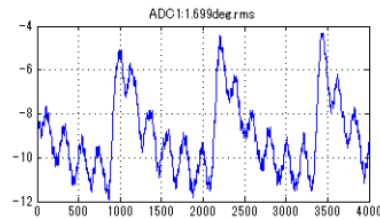
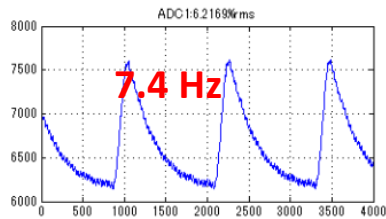
200 W



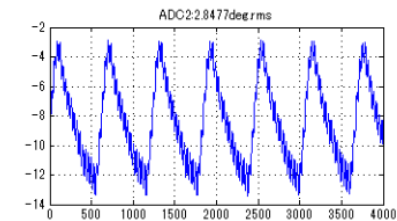
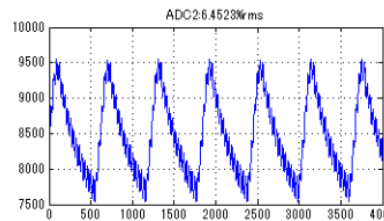
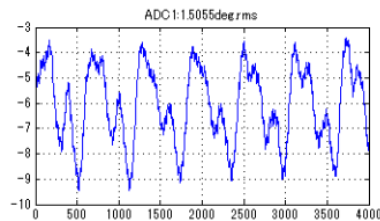
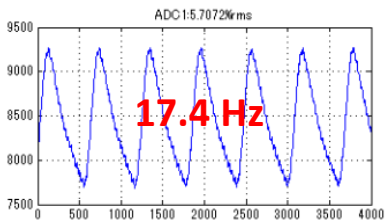
ML2 IOT test

The Waveform in the worst IOT output case (300 W to 500 W)

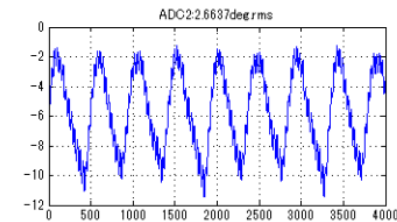
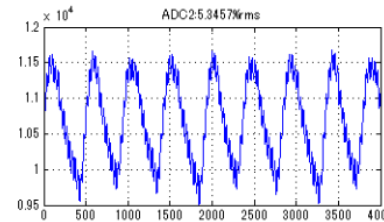
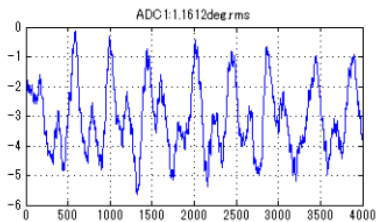
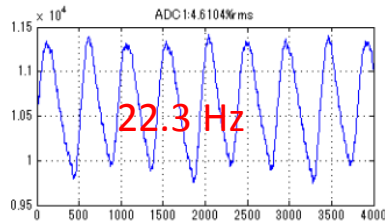
300 W



500 W



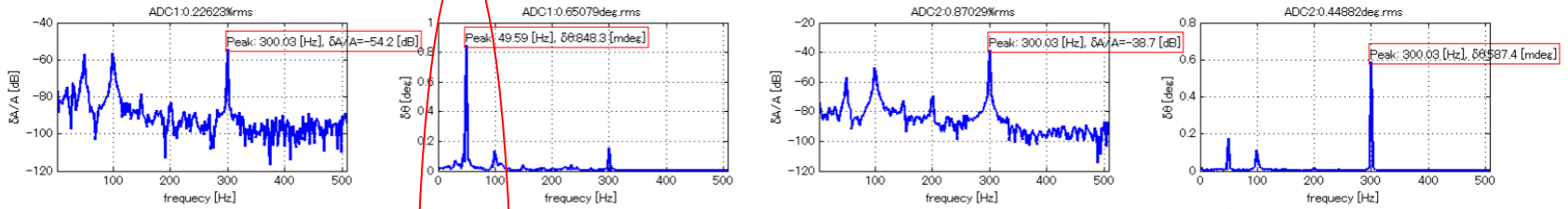
800 W



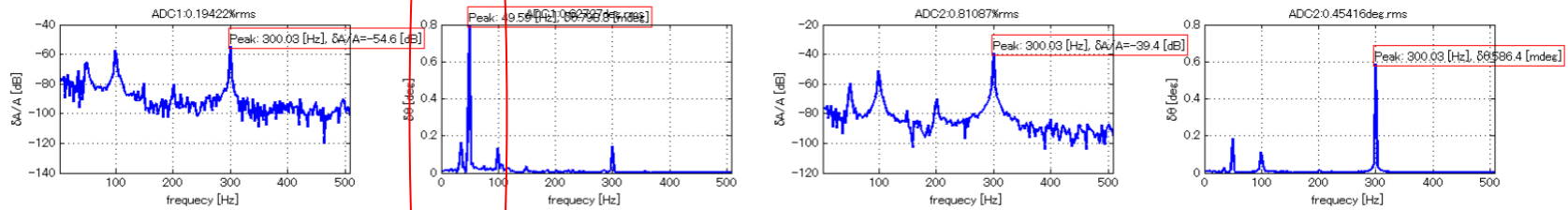
ML2 IOT test

IOT (High power case)

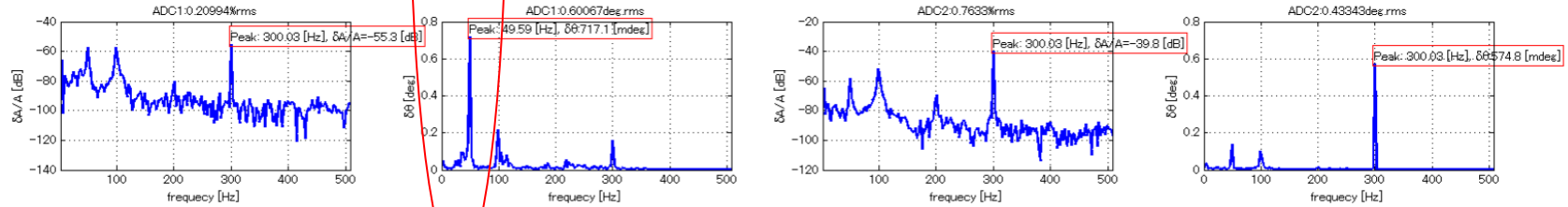
1000 W



1500 W



1800 W



Noted that the 50 Hz component is enhanced from Pf to Pt !

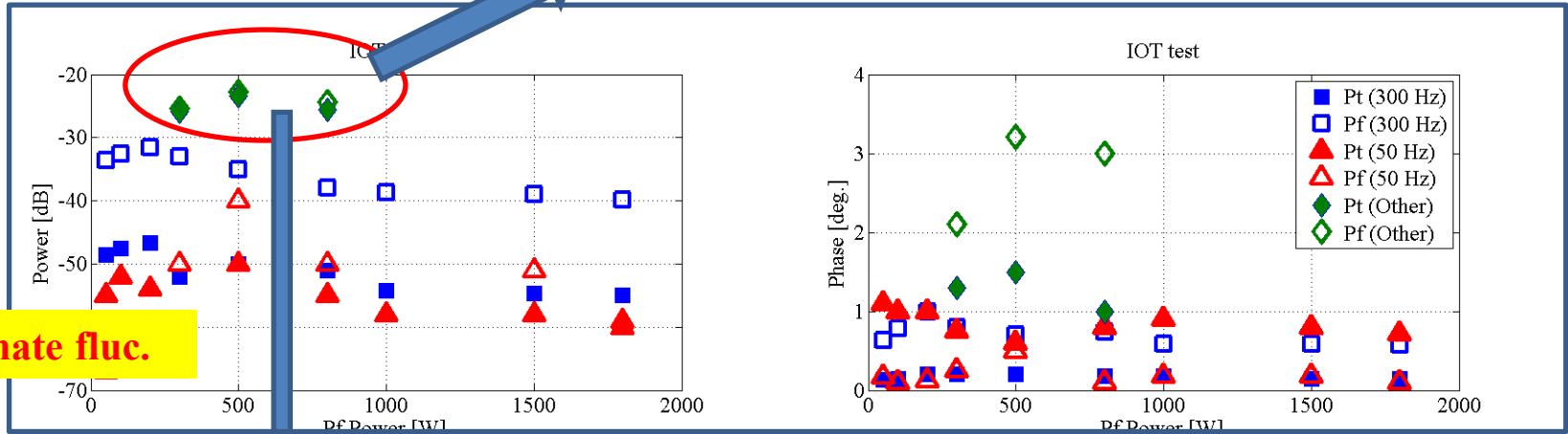
Experiment on ML (ML2 IOT)

The dominated component in different IOT power

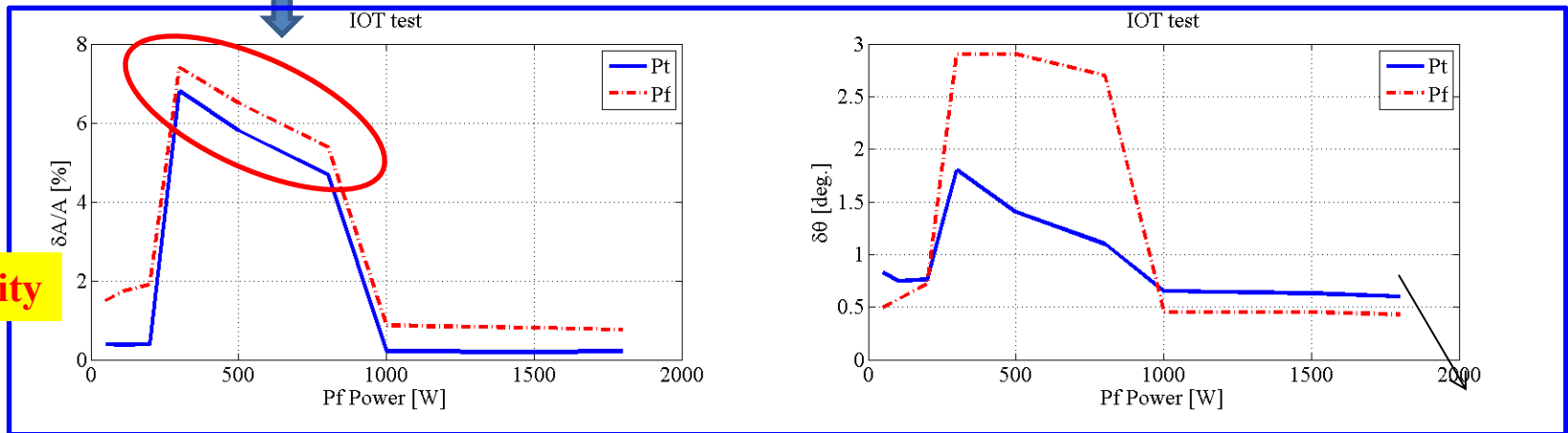
振幅

IOT fluc.

位相



Dominate fluc.



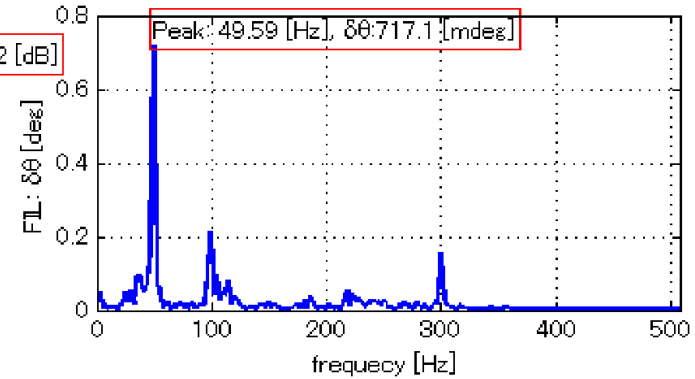
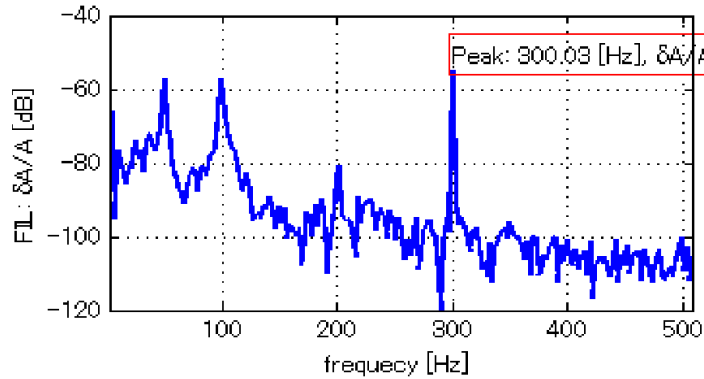
Stability

ML2 (Spectrum)

振幅

位相

FF



FB

